

Resource Summary Report

Generated by RRID on Aug 6, 2026

FEI: flexProber System for Semiconductors

RRID:SCR_019881

Type: Tool

Proper Citation

FEI: flexProber System for Semiconductors (RRID:SCR_019881)

Resource Information

URL: <https://www.fei.com/products/efa/flexprober-for-semiconductors/>

Proper Citation: FEI: flexProber System for Semiconductors (RRID:SCR_019881)

Description: Nanoprobe platform that provides electrical characterization and fault isolation capabilities for process development, device design debug, and failure analysis.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: flexProber System for Semiconductors

Resource ID: SCR_019881

Alternate IDs: Model_Number_flexProber

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190647+0000

Ratings and Alerts

No rating or validation information has been found for FEI: flexProber System for Semiconductors.

No alerts have been found for FEI: flexProber System for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.